

Abstract

A BISR mode and associated method for testing memory. All redundant elements of the memory including the ones which are not used are tested, and interaction between redundant elements of the memory and adjacent functional memory are checked. Repair information is used to repair the memory. In addition, redundant elements which are not needed to be used for repairing the memory are forced to be used, such as by faking defects to remap good elements with redundant elements.